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Wide Temperature Range Version 4 M SRAM (512-kword × 8-bit)



ADE-203-1211C (Z) Rev. 3.0 Dec. 18, 2002

Description

The Hitachi HM628512CI is a 4-Mbit static RAM organized 512-kword \times 8-bit. HM628512CI Series has realized higher density, higher performance and low power consumption by employing CMOS process technology (6-transistor memory cell). The HM628512CI Series offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It has packaged in 32-pin SOP, 32-pin TSOP II and 32-pin DIP.

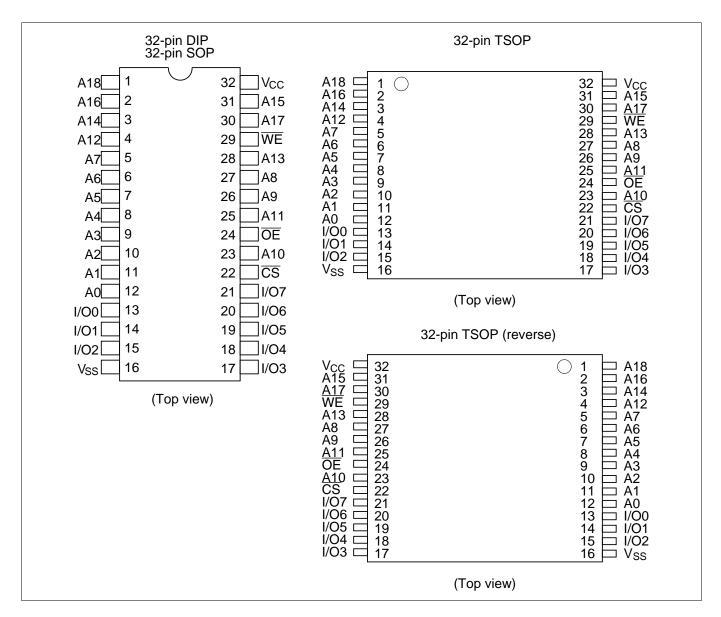
Features

- Single 5 V supply
- Access time: 55/70 ns (max)
- Power dissipation
 - Active: 10 mW/MHz (typ)
 - Standby: 4 μW (typ)
- Completely static memory. No clock or timing strobe required
- Equal access and cycle times
- Common data input and output: Three state output
- Directly TTL compatible: All inputs and outputs
- Battery backup operation
- Operating temperature: -40 to +85°C

Ordering Information

Type No.	Access time	Package
HM628512CLPI-7	70 ns	600-mil 32-pin plastic DIP (DP-32)
HM628512CLFPI-5 HM628512CLFPI-7	55 ns 70 ns	525-mil 32-pin plastic SOP (FP-32D)
HM628512CLTTI-5 HM628512CLTTI-7	55 ns 70 ns	400-mil 32-pin plastic TSOP II (TTP-32D)
HM628512CLRRI-7	70 ns	400-mil 32-pin plastic TSOP II reverse (TTP-32DR)

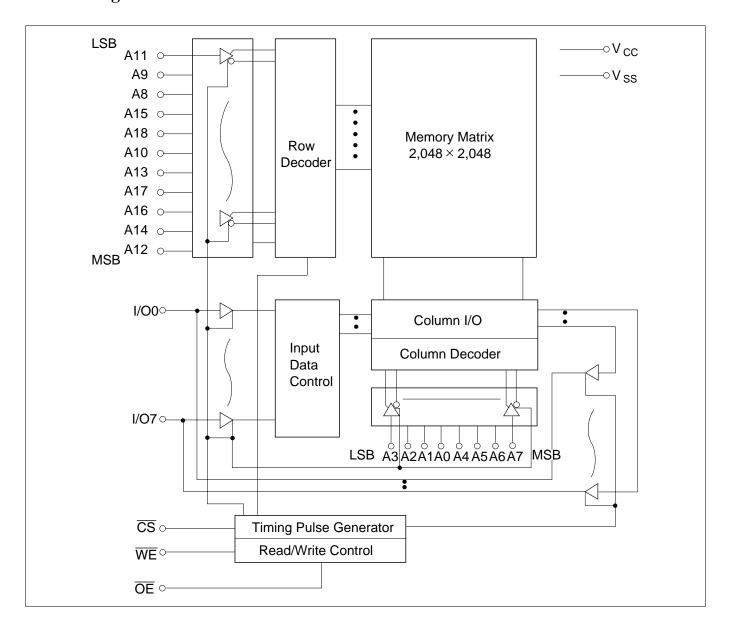
Pin Arrangement



Pin Description

Pin name	Function			
A0 to A18	Address input			
I/O0 to I/O7	Data input/output			
CS	Chip select			
ŌĒ	Output enable			
WE	Write enable			
V _{CC}	Power supply			
V _{SS}	Ground			

Block Diagram



Function Table

WE	CS	OE	Mode	V _{cc} current	Dout pin	Ref. cycle
×	Н	×	Not selected	I_{SB}, I_{SB1}	High-Z	_
Н	L	Н	Output disable	I _{cc}	High-Z	_
Н	L	L	Read	I _{cc}	Dout	Read cycle
L	L	Н	Write	I _{cc}	Din	Write cycle (1)
L	L	L	Write	I _{cc}	Din	Write cycle (2)

Note: x: H or L

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Power supply voltage	V _{cc}	-0.5 to +7.0	V
Voltage on any pin relative to V _{SS}	V _T	-0.5^{*1} to $V_{cc} + 0.3^{*2}$	V
Power dissipation	P _T	1.0	W
Operating temperature	Topr	-40 to +85	°C
Storage temperature	Tstg	-55 to +125	°C
Storage temperature under bias	Tbias	-40 to +85	°C

Notes: 1. V_T min: -3.0 V for pulse half-width ≤ 30 ns.

2. Maximum voltage is 7.0 V.

Recommended DC Operating Conditions ($Ta = -40 \text{ to } +85^{\circ}\text{C}$)

Parameter	Symbol	Min	Тур	Max	Unit
Supply voltage	V _{cc}	4.5	5.0	5.5	V
	V_{ss}	0	0	0	V
Input high voltage	V _{IH}	2.4	_	V _{cc} + 0.3	V
Input low voltage	V _{IL}	-0.3 ^{*1}	_	0.6	V

Note: 1. V_{IL} min: -3.0 V for pulse half-width ≤ 30 ns.

DC Characteristics

Symbol	Min	Typ*1	Max	Unit	Test conditions
I _{LI}	_	_	1	μΑ	$Vin = V_{SS}$ to V_{CC}
I _{LO}	_	_	1	μΑ	$\overline{\text{CS}} = V_{\text{IH}} \text{ or } \overline{\text{OE}} = V_{\text{IH}} \text{ or } \overline{\text{WE}} = V_{\text{IL}}, V_{\text{I/O}} = V_{\text{SS}} \text{ to } V_{\text{CC}}$
I _{cc}	_	1.5	3	mA	$\overline{\text{CS}} = V_{\text{IL}},$ others = $V_{\text{IH}}/V_{\text{IL}}$, $I_{\text{I/O}} = 0 \text{ mA}$
I _{CC1}	_	8	25	mA	$\frac{\text{Min cycle, duty} = 100\%}{\text{CS}} = V_{\text{IL}}, \text{ others} = V_{\text{IH}}/V_{\text{IL}}$ $I_{\text{I/O}} = 0 \text{ mA}$
I _{CC1}	_	7	25	mΑ	
I _{CC2}	_	2	5	mA	$\begin{split} &\text{Cycle time} = 1 \; \mu\text{s}, \\ &\text{duty} = 100\% \\ &\text{I}_{\text{I/O}} = 0 \; \text{mA}, \; \overline{\text{CS}} \leq 0.2 \; \text{V} \\ &\text{V}_{\text{IH}} \geq \text{V}_{\text{CC}} - 0.2 \; \text{V}, \; \text{V}_{\text{IL}} \leq 0.2 \; \text{V} \end{split}$
I _{SB}	_	0.1	0.5	mA	CS = V _{IH}
; I _{SB1}		0.8*2	20*2	μΑ	$Vin \ge 0 \text{ V}, \overline{CS} \ge V_{CC} - 0.2 \text{ V}$
V _{OL}	_		0.4	V	I _{OL} = 2.1 mA
V_{OH}	2.4	_	_	V	$I_{OH} = -1.0 \text{ mA}$
			$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ I_{LI} $ — — 1 μA $ I_{LO} $ — — 1 μA $ I_{CC} $ — 1.5 3 mA $ I_{CC} $ — 8 25 mA $ I_{CC1} $ — 7 25 mA $ I_{CC2} $ — 2 5 mA $ I_{CC2} $ — 0.1 0.5 mA $ I_{SB} $ — 0.8*2 20*2 μA $ I_{CC1} $ — 0.4 V

Notes: 1. Typical values are at $V_{CC} = 5.0 \text{ V}$, $Ta = +25^{\circ}\text{C}$ and specified loading, and not guaranteed.

Capacitance (Ta = +25°C, f = 1 MHz)

Parameter	Symbol	Тур	Max	Unit	Test conditions
Input capacitance*1	Cin	_	8	pF	Vin = 0 V
Input/output capacitance*1	$C_{I/O}$	_	10*2	pF	V _{I/O} = 0 V

Note: 1. This parameter is sampled and not 100% tested.

2. $C_{I/O}$ max = 12 pF only for HM628512CLPI Series.

AC Characteristics (Ta = -40 to +85 °C, V_{CC} = 5 V \pm 10%, unless otherwise noted.)

Test Conditions

• Input pulse levels: 0.4 V to 2.4 V

• Input rise and fall time: 5 ns

• Input and output timing reference levels: 1.5 V

• Output load: $1 \text{ TTL Gate} + C_L (50 \text{ pF}) (HM628512\text{CI-5})$

 $1 \text{ TTL Gate} + C_L (100 \text{ pF}) (HM628512CI-7)$

(Including scope and jig)

Read Cycle

		HM628	3512CI				
		-5		-7			
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Read cycle time	t _{RC}	55	_	70	_	ns	
Address access time	t _{AA}	_	55		70	ns	
Chip select access time	t _{co}	_	55	_	70	ns	
Output enable to output valid	t _{OE}	_	25	_	35	ns	
Chip selection to output in low-Z	t _{LZ}	10	_	10	_	ns	2
Output enable to output in low-Z	t _{OLZ}	5	_	5	_	ns	2
Chip deselection to output in high-Z	t _{HZ}	0	20	0	25	ns	1, 2
Output disable to output in high-Z	t _{OHZ}	0	20	0	25	ns	1, 2
Output hold from address change	t _{oh}	10	_	10	_	ns	

Write Cycle

			_	_
	/162	OEA	2	
-1	nn /	77 1		

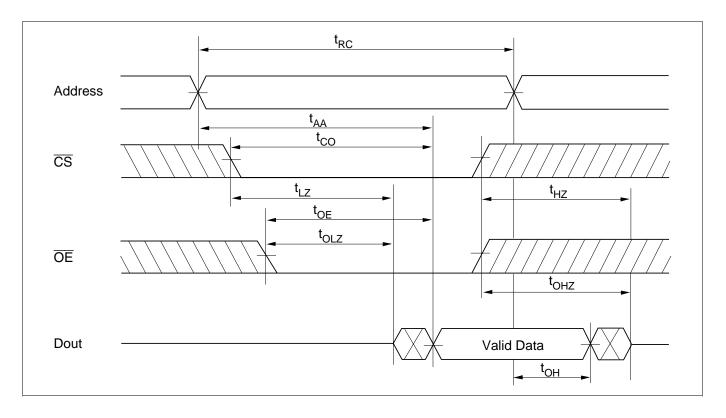
		-5		-7			
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Write cycle time	t _{wc}	55	_	70	_	ns	
Chip selection to end of write	$t_{\scriptscriptstyle \sf CW}$	50	_	60		ns	4
Address setup time	t_{AS}	0	_	0	_	ns	5
Address valid to end of write	t _{AW}	50	_	60	_	ns	
Write pulse width	t _{wP}	40	_	50	_	ns	3, 12
Write recovery time	t _{wR}	0	_	0	_	ns	6
WE to output in high-Z	t_{WHZ}	0	20	0	25	ns	1, 2, 7
Data to write time overlap	t _{DW}	25	_	30	_	ns	
Data hold from write time	t _{DH}	0	_	0	_	ns	
Output active from output in high-Z	t _{ow}	5	_	5	_	ns	2
Output disable to output in high-Z	t _{OHZ}	0	20	0	25	ns	1, 2, 7

Notes: 1. t_{HZ} , t_{OHZ} and t_{WHZ} are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.

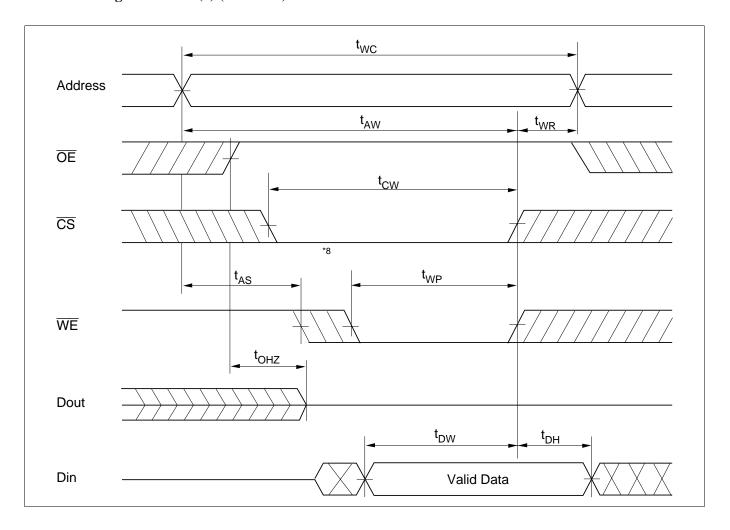
- 2. This parameter is sampled and not 100% tested.
- 3. A write occurs during the overlap (t_{WP}) of a low \overline{CS} and a low \overline{WE} . A write begins at the later transition of \overline{CS} going low or \overline{WE} going low. A write ends at the earlier transition of \overline{CS} going high or \overline{WE} going high. t_{WP} is measured from the beginning of write to the end of write.
- 4. t_{CW} is measured from \overline{CS} going low to the end of write.
- 5. t_{AS} is measured from the address valid to the beginning of write.
- 6. t_{WR} is measured from the earlier of \overline{WE} or \overline{CS} going high to the end of write cycle.
- 7. During this period, I/O pins are in the output state so that the input signals of the opposite phase to the outputs must not be applied.
- 8. If the $\overline{\text{CS}}$ low transition occurs simultaneously with the $\overline{\text{WE}}$ low transition or after the $\overline{\text{WE}}$ transition, the output remain in a high impedance state.
- 9. Dout is the same phase of the write data of this write cycle.
- 10. Dout is the read data of next address.
- 11. If $\overline{\text{CS}}$ is low during this period, I/O pins are in the output state. Therefore, the input signals of the opposite phase to the outputs must not be applied to them.
- 12. In the write cycle with \overline{OE} low fixed, t_{WP} must satisfy the following equation to avoid a problem of data bus contention. $t_{WP} \ge t_{DW}$ min + t_{WHZ} max

Timing Waveforms

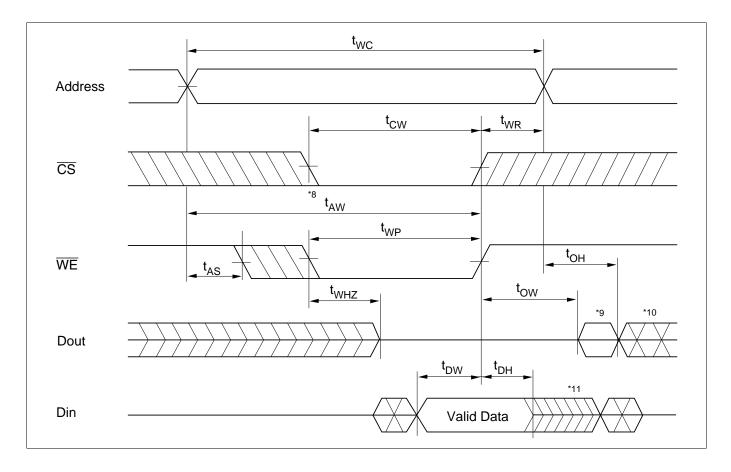
Read Timing Waveform $(\overline{WE}=V_{IH})$



Write Timing Waveform (1) $(\overline{OE} \operatorname{Clock})$



Write Timing Waveform (2) (OE Low Fixed)



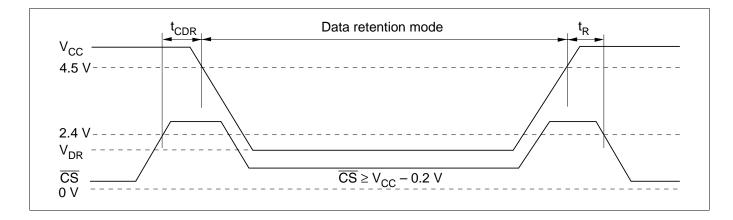
Low V_{CC} **Data Retention Characteristics** ($Ta = -40 \text{ to } +85^{\circ}\text{C}$)

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions*2
V _{cc} for data retention	V_{DR}	2	_	_	V	$\overline{\text{CS}} \ge \text{V}_{\text{CC}} - 0.2 \text{ V, Vin} \ge 0 \text{ V}$
Data retention current	I _{CCDR}	_	0.8*3	20*1	μΑ	$\frac{V_{CC}}{CS} = 3.0 \text{ V}, \text{ Vin } \ge 0 \text{ V}$ $\overline{CS} \ge V_{CC} - 0.2 \text{ V}$
Chip deselect to data retention time	t_{CDR}	0	_	_	ns	See retention waveform
Operation recovery time	t_R	t_{RC}^{*4}	_	_	ns	

Notes: 1. 10 μ A (max) at Ta = -40 to +40°C.

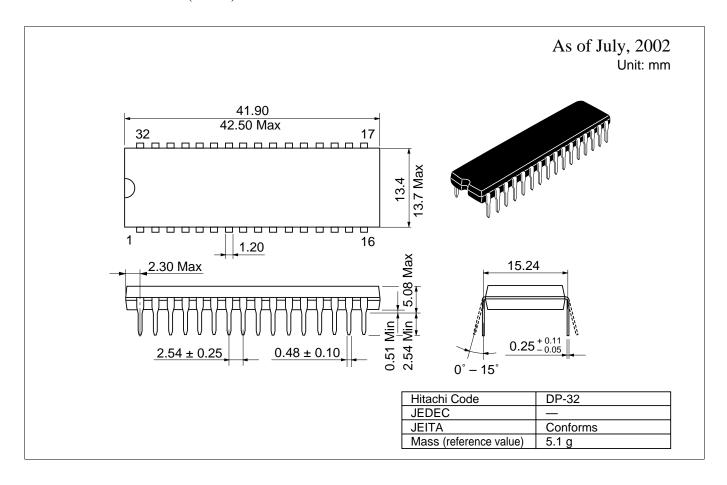
- 2. $\overline{\text{CS}}$ controls address buffer, $\overline{\text{WE}}$ buffer, $\overline{\text{OE}}$ buffer, and Din buffer. In data retention mode, Vin levels (address, $\overline{\text{WE}}$, $\overline{\text{OE}}$, I/O) can be in the high impedance state.
- 3. Typical values are at V_{cc} = 3.0 V, Ta = +25°C and specified loading, and not guaranteed.
- 4. t_{RC} = read cycle time.

Low V_{CC} Data Retention Timing Waveform (\overline{CS} Controlled)



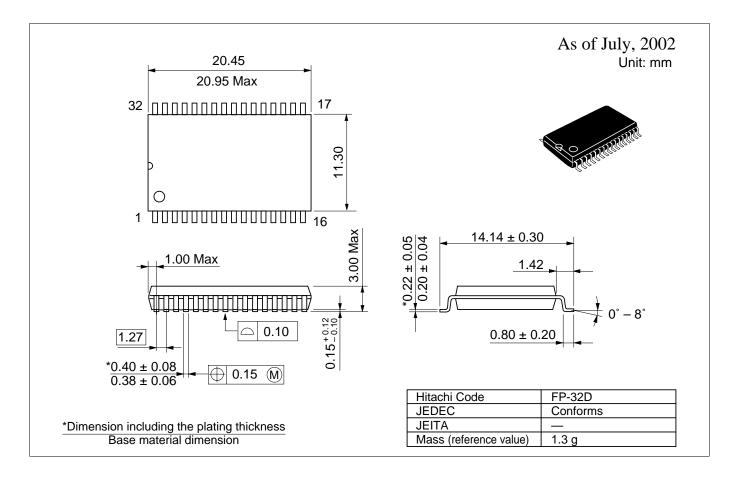
Package Dimensions

HM628512CLPI Series (DP-32)



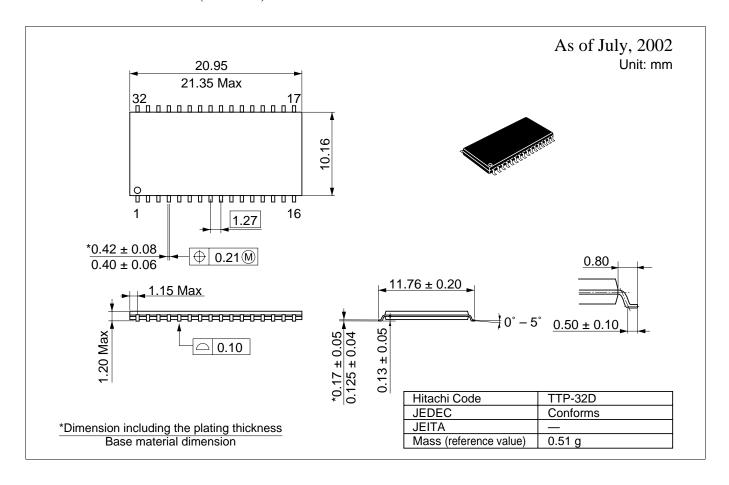
Package Dimensions (cont.)

HM628512CLFPI Series (FP-32D)



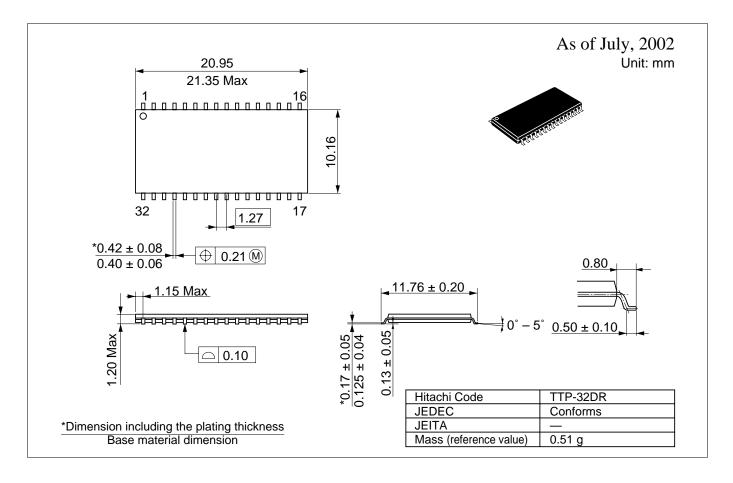
Package Dimensions (cont.)

HM628512CLTTI Series (TTP-32D)



Package Dimensions (cont.)

HM628512CLRRI Series (TTP-32DR)



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